





TEST REPORT

No. I19Z70327-EMC02

for

Samsung Electronics. Co., Ltd.

Mobile phone

Model Name: SM-A015T1

FCC ID: ZCASMA015T1

with

Hardware Version: REV3.0

Software Version: A015T1.001 (A015T1UVE0ASJ6)

Issued Date: 2020-02-11

Note:

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Test Laboratory:

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REPORT HISTORY

Report Number	Revision	Description	Issue Date
I19Z70327-EMC02	Rev.0	1 st edition	2020-02-11

Note: the latest revision of the test report supersedes all previous version.





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1. Test Laboratory

1.1. Introduction & Accreditation

Telecommunication Technology Labs, CAICT is an ISO/IEC 17025:2005 accredited test laboratory under NATIONAL VOLUNTARY LABORATORY ACCREDITATION PROGRAM (NVLAP) with lab code 600118-0, and is also an FCC accredited test laboratory (CN5017), and ISED accredited test laboratory (CN0066). The detail accreditation scope can be found on NVLAP website.

2. Test Laboratory

2.1. Testing Location

CTTL(huayuan North Road)

Address:

No. 52, Huayuan North Road, Haidian District, Beijing, P. R. China100191

2.2. Testing Environment

Normal Temperature:	15-35° C
Relative Humidity:	20-75%

2.3. Project data

Testing Start Date:	2019-11-11
Testing End Date:	2019-12-16

2.4. Signature

王公

Wang Junqing (Prepared this test report)

张幕

Zhang Ying (Reviewed this test report)

21 13. 4.2

Liu Baodian Deputy Director of the laboratory (Approved this test report)





3. Client Information

3.1. Applicant Information

Company Name:	Samsung Electronics. Co., Ltd.		
A data a a u	R5, A Tower 22 Floor A-1,(Maetan dong)		
Address: 129,Samsung-ro,Yeongtong-gu, Suwon-Si, Gyeonggi-do 16677, Ko			
Contact Person	JP KIM		
Contact Email	jp426.kim@samsung.com		
Telephone:	+82-10-4376-0326		
Fax:	/		

3.2. Manufacturer Information

Company Name:	Samsung Electronics. Co., Ltd.	
Address:	R5, A Tower 22 Floor A-1,(Maetan dong)	
Address.	129,Samsung-ro,Yeongtong-gu, Suwon-Si, Gyeonggi-do 16677, Korea	
Contact Person	JP KIM	
Contact Email	jp426.kim@samsung.com	
Telephone:	+82-10-4376-0326	
Fax:	/	





4. Equipment Under Test (EUT) and Ancillary Equipment (AE)

4.1. About EUT

Description	Mobile phone
Model Name	SM-A015T1
FCC ID	ZCASMA015T1
Extreme vol. Limits	3.6VDC to 4.2VDC (nominal: 3.85VDC)

Note: Components list, please refer to documents of the manufacturer; it is also included in the original test record of CTTL,Telecommunication Technology Labs, CAICT.

4.2. Internal Identification of EUT used during the test

EUT ID*	SN or IMEI	HW Version	SW Version
EUT1	351765110000166	REV3.0	A015T1.001
EUTI	331703110000100	REV3.0	(A015T1UVE0ASJ6)
EUT3	351765110000117	REV3.0	A015T1.001
		REV3.0	(A015T1UVE0ASJ6)

*EUT ID: is used to identify the test sample in the lab internally.

AE ID*	Description	SN	Remarks	
AE1	Battery	/	/	
AE2	Battery	/	/	
AE3	Charger	/	315	
AE4	Charger	/	929	
AE5	Charger	/	941	
AE6	USB Cable	/	/	
AE7	Headset	/	/	
AE10	OTG Cable	/	/	
AE1				
Model		QL1695		
Manufacturer		Ningde Am	Ningde Amperex Technology Limited	
Capacitance /		/	/	
Nominal voltage 3.85 \		3.85 V		
AE2				
Model		QL1695		
Manufacturer		SCUD(Fuji	SCUD(Fujian) Electronics Co., Ltd.	
Capacitance /				
Nomina	l voltage	3.85 V		
AE3				
Model	Model EP-TA50JWE		VE	
Manufad	Manufacturer DongYang E&P Inc.		E&P Inc.	
Length of	of cable	/	/	

4.3. Internal Identification of AE used during the test

AE4





Model	EP-TA50JWE
Manufacturer	HAEM Co.,Ltd
Length of cable	/
AE5	
Model	EP-TA50JWE
Manufacturer	RF Tech
Length of cable	/
AE6	
Model	EP-DR140AWE
Manufacturer	LUXSHARE-ICT (VIETNAM) LIMITED
Length of cable	/
AE7	
Model	EHS61ASFWE
Manufacturer	DONGGUAN YOUNGBO ELECTRONICS CO., LTD
Length of cable	/
AE10	
Model	/
Manufacturer	/
Length of cable	/
*AE ID: is used to identify the test	sample in the lab internally.

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Note: The USB cables are shielded.





4.4. EUT set-ups

EUT set-up No.	Combination of EUT and AE	Remarks
Set.8	EUT1+ AE1/AE2+ AE4+ AE6	Charger

Note: Mobile phone SM-A015T1 manufactured by Samsung Electronics. Co., Ltd. is a variant model based on SM-A015V for conformance test. According to the declaration of changes, adding the tests as follow:

Test Item	Mode
Radiated Emission	LTE band 71

no test needs to been performed, all results are cited from the initial model. The report number for initial model is I19Z70303-EMC02.





5. <u>Reference Documents</u>

5.1. Reference Documents for testing

The following documents listed in this section are referred for testing.								
Reference	Title	Version						
FCC Part 15, Subpart B	Radio frequency devices - Unintentional Radiators	2016						
ANSI C63.4	American National Standard for	2014						
	Methods of Measurement of Radio-							
	Noise Emissions from Low-Voltage							
Electrical and Electronic Equipment								
	in the Range of 9 kHz to 40 GHz							

Note: The test methods have no deviation with standards.





6. LABORATORY ENVIRONMENT

Semi-anechoic chamber SAC-1 (23 meters×17meters×10meters) did not exceed following limits along the EMC testing:

Temperature	Min. = 15 °C, Max. = 35 °C
Relative humidity	Min. = 15 %, Max. = 75 %
Shielding effectiveness	0.014MHz-1MHz, >60dB;
	1MHz - 1000MHz, >90dB.
Electrical insulation	> 2 MΩ
Ground system resistance	<4 Ω
Normalised site attenuation (NSA)	< ±4 dB, 10 m distance
Site voltage standing-wave ratio (S _{VSWR})	Between 0 and 6 dB, from 1GHz to 6GHz
Uniformity of field strength	Between 0 and 6 dB, from 80 to 3000 MHz

Shielded room did not exceed following limits along the EMC testing:

Temperature	Min. = 15 °C, Max. = 35 °C			
Relative humidity	Min. = 20 %, Max. = 75 %			
Shielding effectiveness	0.014MHz-1MHz, >60dB;			
	1MHz-1000MHz, >90dB.			
Electrical insulation	> 2 MΩ			
Ground system resistance	<4 Ω			





7. SUMMARY OF TEST RESULTS

Abbreviations used in this clause:		
	Р	Pass
Verdict Column	NA	Not applicable
	F	Fail

ltems	Test Name	Clause in FCC rules	Section in this report	Verdict	Test Location
1	Radiated Emission	15.109(a)	B.1	Р	CTTL(huayuan North Road)





8. Test Equipments Utilized

			SERIES		CAL DUE	CALIBRATI
NO.	Description	TYPE	NUMBER	MANUFACTURE	DATE	ON
			NUMBER			INTERVAL
1	Test Receiver	ESU26	100235	R&S	2020-03-01	1 Year
	Universal Radio					
2	Communication	CMW500	150344	R&S	2020-11-17	1 year
	Tester					
	Universal Radio					
3	Communication	CMW500	116588	R&S	2020-12-26	1 year
	Tester					
4	EMI Antenna	VULB 9163	9163-1222	Schwarzbeck	2020-03-14	1 year





ANNEX A: MEASUREMENT RESULTS

A.1 Radiated Emission Reference FCC: CFR Part 15.109(a).

A.1.1 Method of measurement

The field strength of radiated emissions from the unintentional radiator at distances of 10 meters(for 30MHz-1GHz). Tested in accordance with the procedures of ANSI C63.4 – 2014, section 8.3.

The EUT was placed on a non-conductive table. The measurement antenna was placed at a distance of 3/10 meters from the EUT. During the tests, the antenna height and the EUT azimuth were varied in order to identify the maximum level of emissions from the EUT. This maximization process was repeated with the EUT positioned in each of its three orthogonal orientations.

A.1.2 EUT Operating Mode

The MS is operating in the charging mode and transmitter receiver mode.

A.1.3 Measurement Limit

Frequency range	Field strength limit (µV/m)					
(MHz)	Quasi-peak	Average	Peak			
30-88	100					
88-216	150					
216-960	200					
960-1000	500					
>1000		500	5000			

Note: the above limit is for 3 meters test distance. 10 meters' limit is got by converting.

A.1.4 Test Condition

Frequency range (MHz)	RBW/VBW	Sweep Time (s)	Detector
30-1000	120kHz (IF Bandwidth)	5	Peak/Quasi-peak





A.1.5 Measurement Results

A "reference path loss" is established and the A_{Rpl} is the attenuation of "reference path loss". It includes the antenna factor of receive antenna and the path loss.

The measurement results are obtained as described below:

 $Result = P_{Mea} + A_{Rpl} = P_{Mea} + G_A + G_{PL}$

Where

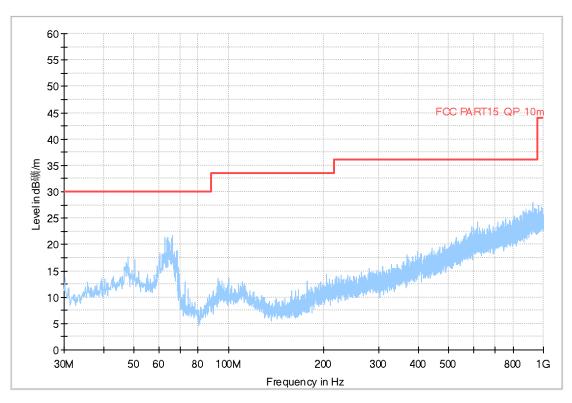
G_A: Antenna factor of receive antenna

G_{PL}: Path Loss

P_{Mea}: Measurement result on receiver.

Measurement uncertainty (worst case): U = 5.44 dB, k=2.

Charging Mode, GSM850MHz, idle, channel 128



Full Spectrum

Fig A.1 Radiated Emission from 30MHz to 1GHz, GSM850MHz, idle, channel 128





Charging Mode, GSM850MHz, idle, channel 190

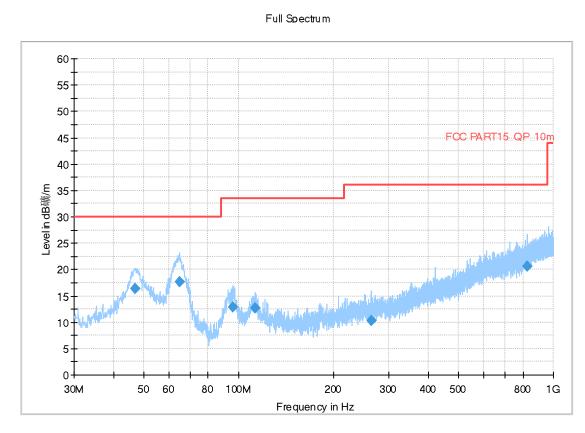


Fig A.2	Radiated Emission from 30MHz to 1GHz, GSM850MHz, idle, channel 190
Final_Res	sult

Frequency	QuasiPeak	Limit	Margin	Meas.	Bandwidth	Height	Pol	Azimuth
(MHz)	(dBuV/m)	(dBuV/m)	(dB)	Time	(kHz)	(cm)		(deg)
				(ms)				
46.846000	16.37	30.00	13.63	1000.0	120.000	125.0	v	263.0
65.077000	17.71	30.00	12.29	1000.0	120.000	104.0	v	183.0
95.905000	12.80	33.50	20.72	1000.0	120.000	179.0	v	261.0
112.662000	12.62	33.50	20.90	1000.0	120.000	125.0	v	255.0
263.271000	10.28	36.00	25.74	1000.0	120.000	125.0	v	90.0
824.675000	20.69	36.00	15.33	1000.0	120.000	125.0	v	-30.0





Charging Mode, GSM850MHz, idle, channel 251

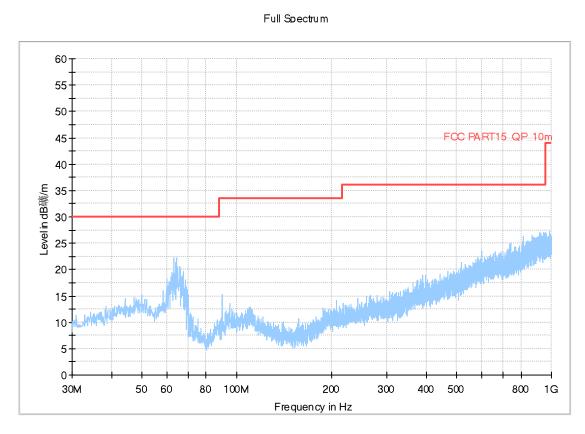
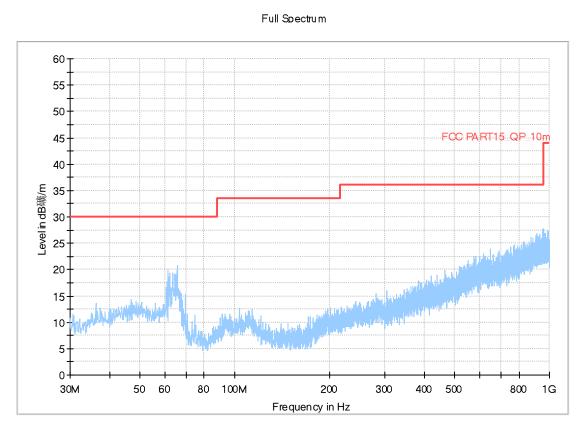


Fig A.3 Radiated Emission from 30MHz to 1GHz, GSM850MHz, idle, channel 251







Charging Mode, WCDMA850MHz, idle, channel 4132

Fig A.4 Radiated Emission from 30MHz to 1GHz, WCDMA850MHz, idle, channel 4132





Charging Mode, WCDMA850MHz, idle, channel 4183

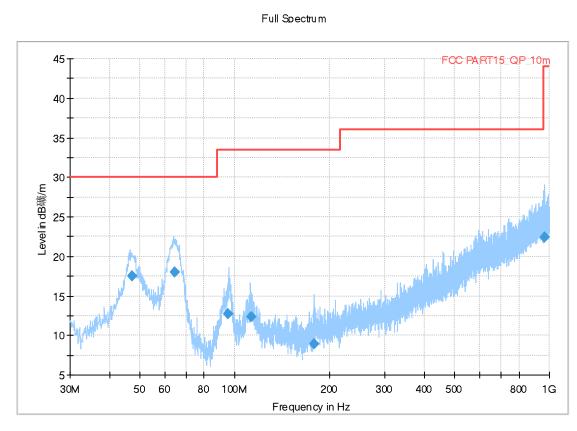
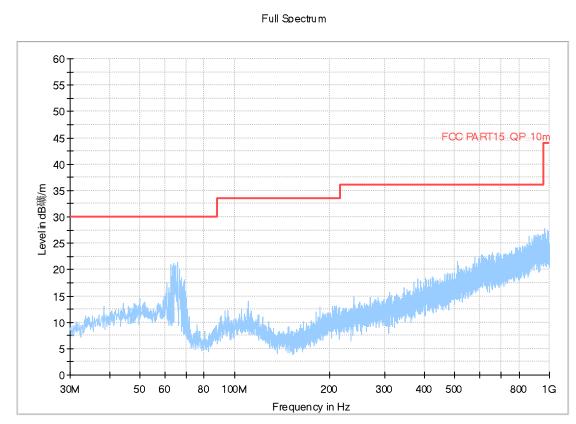


Fig A.5 Radiated Emission from 30MHz to 1GHz, WCDMA850MHz, idle, channel 4183
Final_Result

Frequency	QuasiPeak	Limit	Margin	Meas.	Bandwidth	Height	Pol	Azimuth
(MHz)	(dBuV/m)	(dBuV/m)	(dB)	Time	(kHz)	(cm)		(deg)
				(ms)				
47.261000	17.47	30.00	12.53	1000.0	120.000	111.0	v	-5.0
64.333000	18.04	30.00	11.96	1000.0	120.000	225.0	v	-12.0
95.152000	12.68	33.50	20.84	1000.0	120.000	102.0	v	287.0
112.893000	12.38	33.50	21.14	1000.0	120.000	125.0	v	265.0
178.267000	8.87	33.50	24.65	1000.0	120.000	119.0	v	8.0
962.794000	22.43	44.00	21.55	1000.0	120.000	325.0	v	168.0







Charging Mode, WCDMA850MHz, idle, channel 4233

Fig A.6 Radiated Emission from 30MHz to 1GHz, WCDMA850MHz, idle, channel 4233





Charging Mode, LTE band 5, idle, channel 20407

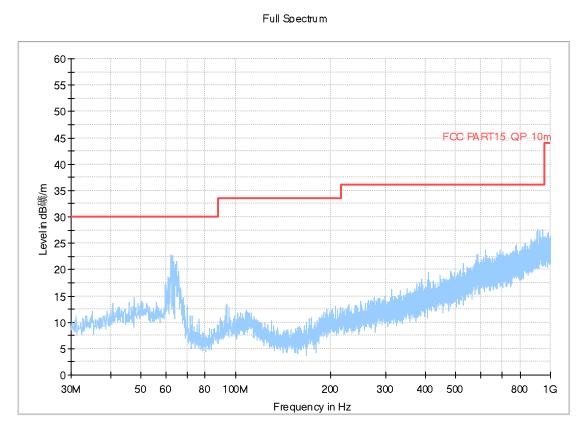


Fig A.7 Radiated Emission from 30MHz to 1GHz, LTE band 5, idle, channel 20407





Charging Mode, LTE band 5, idle, channel 20525

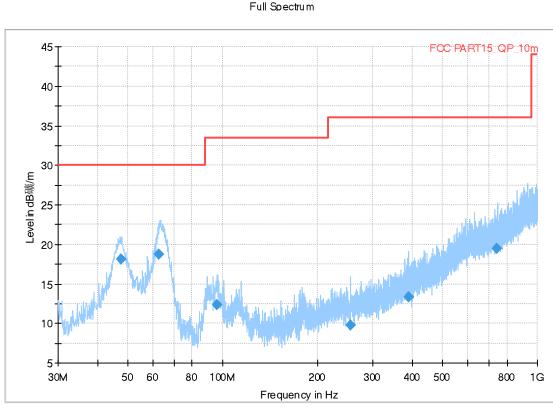


Fig A.8	Radiated Emission from 30MHz to 1GHz, LTE band 5, idle, channel 20525
Final_Res	sult

Frequency	QuasiPeak	Limit	Margin	Meas.	Bandwidth	Height	Pol	Azimuth
(MHz)	(dBuV/m)	(dBuV/m)	(dB)	Time	(kHz)	(cm)		(deg)
				(ms)				
47.428000	18.13	30.00	11.87	1000.0	120.000	102.0	v	151.0
62.814000	18.72	30.00	11.28	1000.0	120.000	102.0	v	151.0
95.734000	12.35	33.50	21.17	1000.0	120.000	125.0	v	-30.0
255.534000	9.81	36.00	26.21	1000.0	120.000	288.0	v	30.0
390.240000	13.35	36.00	22.67	1000.0	120.000	282.0	v	107.0
745.029000	19.44	36.00	16.58	1000.0	120.000	125.0	v	30.0





Charging Mode, LTE band 5, idle, channel 20643

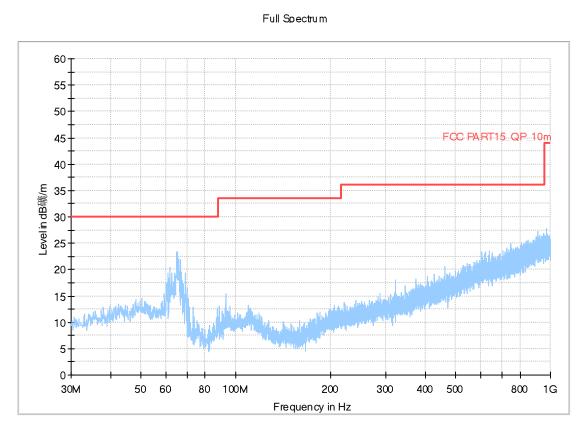


Fig A.9 Radiated Emission from 30MHz to 1GHz, LTE band 5, idle, channel 20643





Charging Mode, LTE band 71, idle, channel 133147

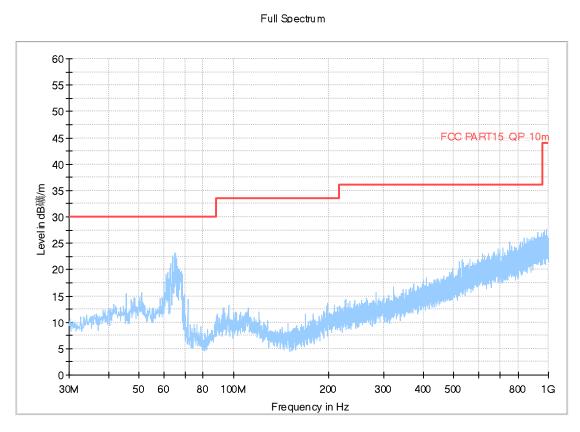


Fig A.10 Radiated Emission from 30MHz to 1GHz, LTE band 71, idle, channel 133147





Charging Mode, LTE band 71, idle, channel 133297

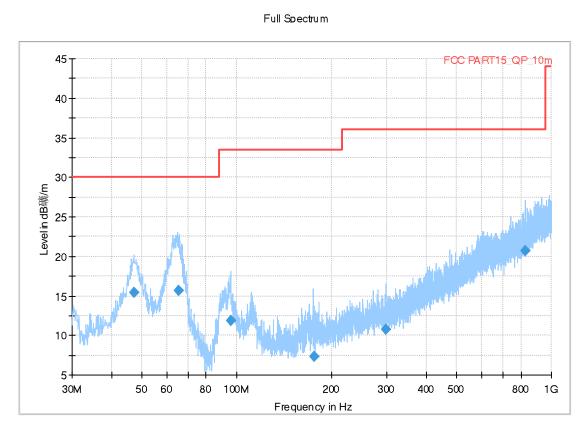


Fig A.11 Radiated Emission from 30MHz to 1GHz, LTE band 71, idle, channel 133297
Final_Result

Frequency	QuasiPeak	Limit	Margin	Meas.	Bandwidth	Height	Pol	Azimuth
(MHz)	(dBuV/m)	(dBuV/m)	(dB)	Time	(kHz)	(cm)		(deg)
				(ms)				
47.132000	15.40	30.00	14.60	1000.0	120.000	125.0	v	-30.0
65.423000	15.68	30.00	14.32	1000.0	120.000	225.0	v	-2.0
95.752000	11.84	33.50	21.68	1000.0	120.000	121.0	v	-17.0
175.777000	7.33	33.50	26.19	1000.0	120.000	196.0	v	-29.0
298.459000	10.80	36.00	25.22	1000.0	120.000	213.0	v	115.0
826.264000	20.73	36.00	15.29	1000.0	120.000	193.0	v	240.0





Charging Mode, LTE band 71, idle, channel 133447

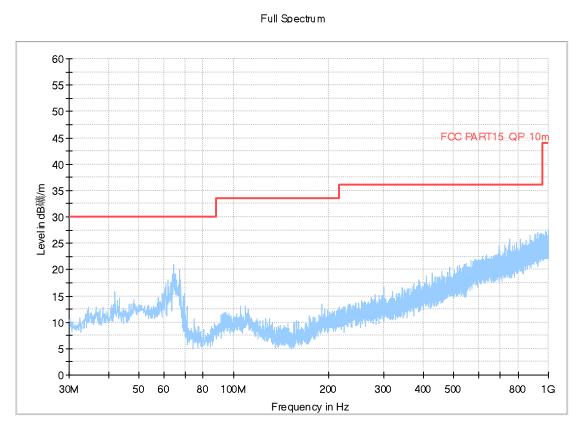


Fig A.12 Radiated Emission from 30MHz to 1GHz, LTE band 71, idle, channel 133447





ANNEX B: PERSONS INVOLVED IN THIS TESTING

Test Item	Test Software and Version	Software Vendor	Test operator	
Radiated Emission	EMC32 V9.01.00	R&S	Yan Hanchen	

END OF REPORT